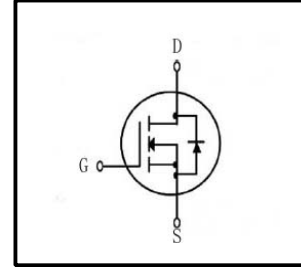


Silicon N-Channel MOSFET

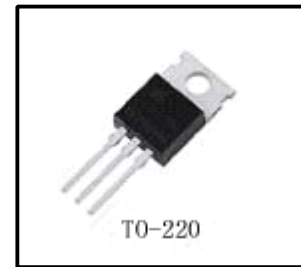
Features

- $R_{DS(on)}$ (Max0.015 Ω)@ $V_{GS}=10V$
- Gate Charge(Typical 80 nC)
- Maximum Junction Temperature Range(175 $^{\circ}C$)



General Description

This Power MOSFET is produced using Winsemi's advanced planar stripe, DMOS technology. This latest technology has been especially designed to minimize on-state resistance, have a low gate charge with superior switching performance, and rugged avalanche characteristics. This Power MOSFET is well suited for synchronous DC-DC Converters and power Management in portable and battery operated products.



Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V_{DSS}	Drain to Source Voltage	80	V
I_D	Continuous Drain Current(@ $T_C=25^{\circ}C$)	75	A
	Continuous Drain Current(@ $T_C=100^{\circ}C$)	52.5	A
I_{DM}	Drain Current Pulsed	300	A
V_{GS}	Gate to Source Voltage	± 20	V
E_{AS}	Single Pulsed Avalanche Energy	1310	mJ
E_{AR}	Repetitive Avalanche Energy	17.3	mJ
dv/dt	Peak Diode Recovery dv/dt	7.0	V/ns
P_D	Total Power Dissipation(@ $T_C=25^{\circ}C$)	173	W
	Derating Factor above 25 $^{\circ}C$	1.15	W/ $^{\circ}C$
T_{STG}	Operating Junction Temperature	-55~175	$^{\circ}C$
T_J	Storage Temperature	150	$^{\circ}C$

Thermal Characteristics

Symbol	Parameter	Value			Units
		Min.	Typ.	Max.	
R_{QJC}	Thermal Resistance, Junction-to-Case	-	-	0.87	$^{\circ}C/w$
R_{QJA}	Thermal Resistance, Junction-to-Ambient*	-	0.5	-	$^{\circ}C/w$
R_{QJA}	Thermal Resistance, Junction-to-Ambient	-	-	62.5	$^{\circ}C/w$

Electrical Characteristics $T_C=25^\circ\text{C}$

Characteristics	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V$, $I_D=250\mu A$	80	-	-	V
Breakdown Voltage Temperature coefficient	$\Delta BV_{DSS}/\Delta T_J$	$I_D=250\mu A$, referenced to 25°C	-	0.08	-	V/ $^\circ\text{C}$
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=80V$, $V_{GS}=0V$	-	-	10	μA
		$V_{DS}=64V$, $T_C=125^\circ\text{C}$	-	-	100	μA
Gate-Source Leakage, Forward	I_{GSS}	$V_{GS}=20V, V_{DS}=0V$	-	-	100	nA
Gate-Source Leakage, Reverse		$V_{GS}=-20V, V_{DS}=0V$	-	-	-100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	2.0	-	4.0	V
Static Drain-Source On-state Resistance	$R_{DS(ON)}$	$V_{GS}=10V$, $I_D=37.5A$	-	0.012	0.015	Ω
Input Capacitance	C_{iss}	$V_{GS}=0V$,	-	2600	3380	pF
Output Capacitance	C_{oss}	$V_{DS}=25V$,	-	940	1220	
Reverse Transfer Capacitance	C_{riss}	$f=1\text{MHz}$	-	210	275	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=40V$,	-	30	70	ns
Rise Time	t_r	$I_D=75A, R_G=25\Omega$	-	225	460	
Turn-off Delay Time	$t_{d(off)}$	Pulse Width $\leq 300\mu s$,	-	165	340	
Fall Time	t_f	$Q > 50$	-	155	320	
Total Gate Charge	Q_g	$V_{DS}=64V$,	-	80	105	nC
Gate-Source Charge	Q_{gs}	$V_{GS}=10V$,	-	15	-	
Gate-Drain Charge (Miller Charge)	Q_{gd}	$I_D=75A$	-	32	-	

Source-Drain Ratings and Characteristics

Characteristics	Symbol	Test Conditions	Min	Typ	Max	units
Maximum Continuous Source-Drain Diode Forward Current	I_S	-	-	-	75	A
Maximum Pulsed Source-Drain Diode Forward	I_{SM}	-	-	-	300	
Diode Forward voltage	V_{SD}	$I_S=75A, V_{GS}=0V$	-	-	1.5	V
Reverse Recovery Time	t_{rr}	$I_S=75A, V_{GS}=0V$,	-	90	-	ns
Reverse Recovery Charge	Q_{rr}	$dI/dt=100A/\mu s$	-	250	-	μC

- Notes:
1. Repeatability rating: pulse width limited by junction temperature
 2. $L=0.32\text{mH}, I_{AS}=75A, V_{DD}=50V, R_G=25\Omega$, Starting $T_J=25^\circ\text{C}$
 3. $I_{SD} \leq 75A, di/dt \leq 300A/\mu s, V_{DD} \leq BV_{DSS}$, Starting $T_J=25^\circ\text{C}$

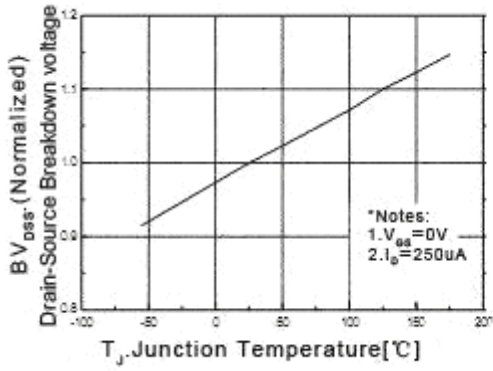


Fig1. Breakdown Voltage Variation vs. Junction temperature

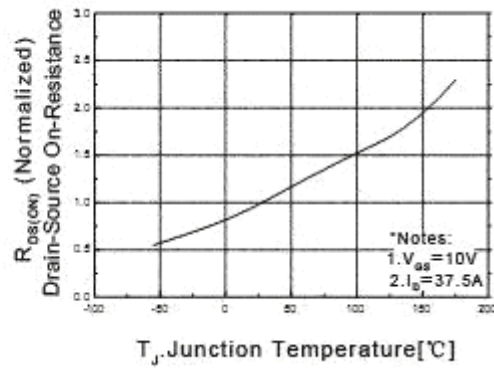


Fig2. On-Resistance Variation vs. Junction Temperature

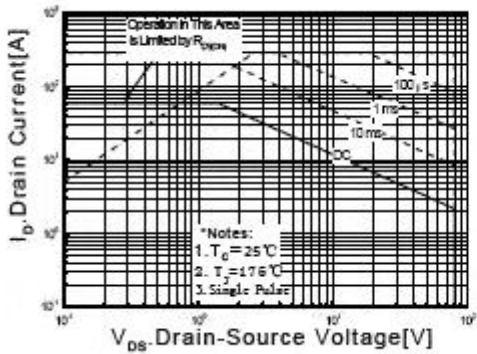


Fig3. Maximum Safe Operating Area

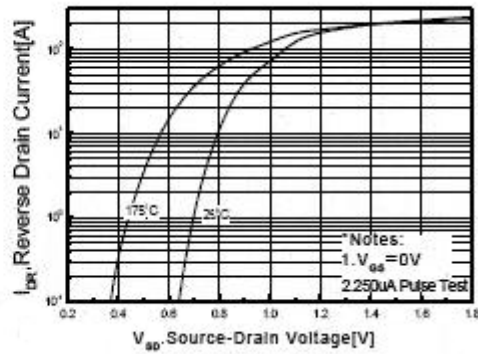


Fig4. On State Current vs. Allowable Case Temperature

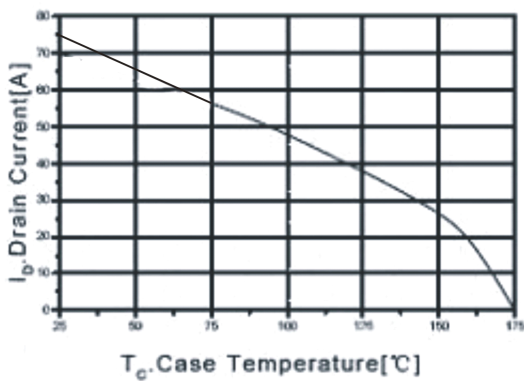


Fig5. Maximum Drain Current vs. Case Temperature

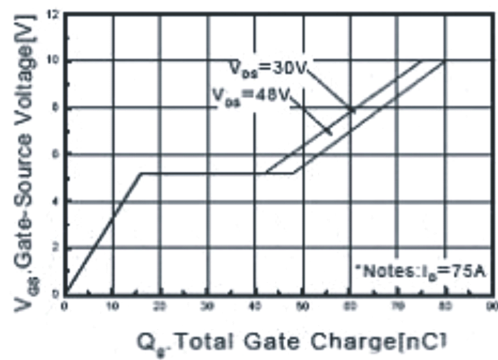


Fig6. Gate Charge Characteristics

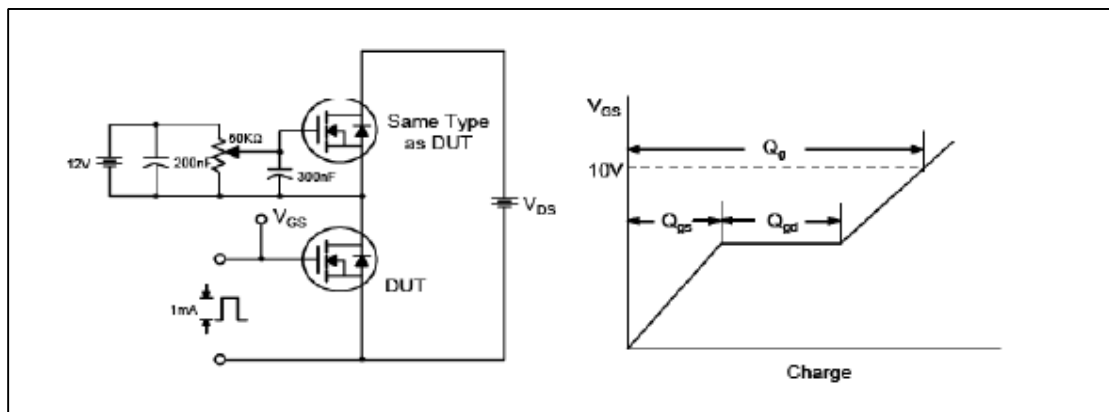


Fig.7 Gate Charge Test Circuit&Waveforms

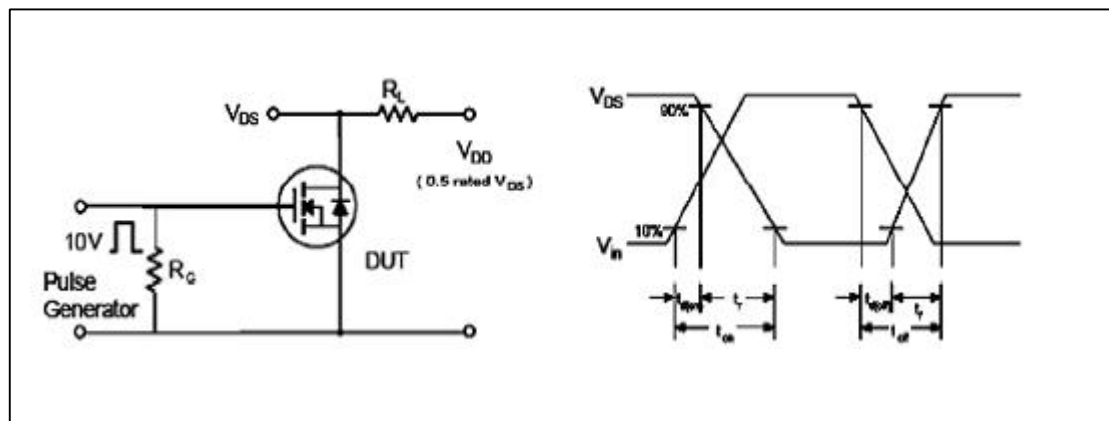


Fig8.Switching Time Test Circuit&Waveforms

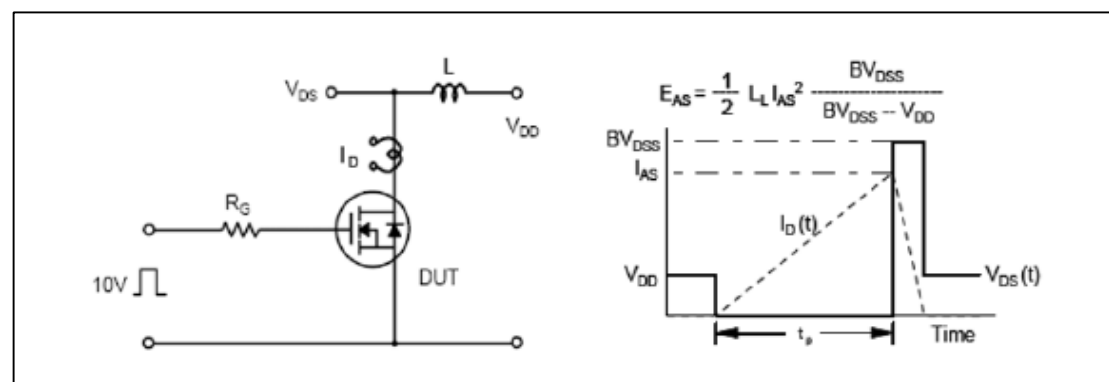


Fig9.Unclamped Inductive Switching Test Circuit&Waveforms

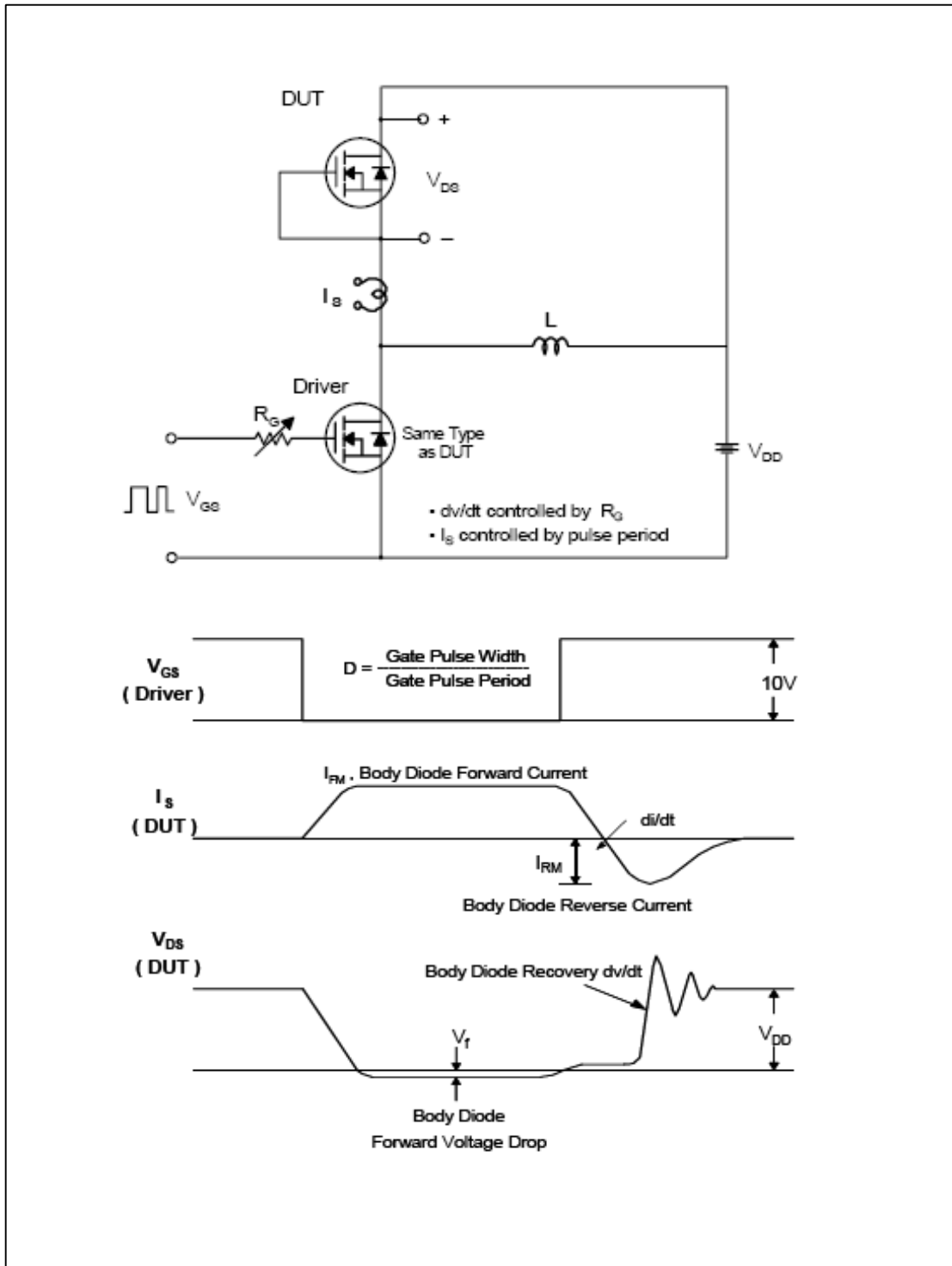


Fig10. Peak Diode Recovery dy/dt Test Circuit&Waveforms

To-220 Package Dimension

